# Memory FRAM

# 128K (16K × 8) Bit SPI MB85RS128TY

# DESCRIPTION

MB85RS128TY is a FRAM (Ferroelectric Random Access Memory) chip in a configuration of 16,384 words  $\times$  8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells. This product is specifically targeted for high-temperature environment such as automotive applications.

MB85RS128TY adopts the Serial Peripheral Interface (SPI).

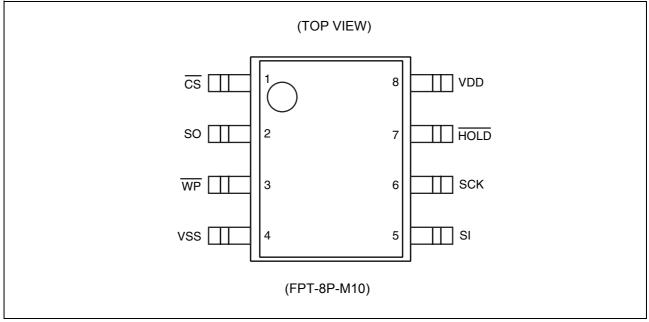
The MB85RS128TY is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS128TY can be used for 10<sup>13</sup> read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E<sup>2</sup>PROM. As MB85RS128TY does not need any waiting time in writing process, the write cycle time of MB85RS128TY is much shorter than that of Flash memories or E<sup>2</sup>PROM.

#### FEATURES

<ul><li>Bit configuration</li><li>Serial Peripheral Interface</li></ul>	<ul> <li>: 16,384 words × 8 bits</li> <li>: SPI (Serial Peripheral Interface)</li> <li>Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)</li> </ul>
Operating frequency	: 33 MHz (Max)
<ul><li>High endurance</li><li>Data retention</li></ul>	: 10 <sup>13</sup> times / byte : 30 years (+85 °C),
	8.2 years (+105 °C),
	2.5 years (+125 °C) or more
Operating power supply voltage	Under evaluation for more than 2.5 years (+125 $^\circ C)$ : 1.8 V to 3.6 V
Low power consumption	: Operating power supply current 2.3 mA (Max@33 MHz) Standby current 45 μA (Max)
	Sleep current 12 µA (Max)
<ul> <li>Operation ambient temperature r</li> </ul>	ange : – 40 °C to +125 °C
Package	: 8-pin plastic SOP (FPT-8P-M10)
	RoHS compliant



# ■ PIN ASSIGNMENT

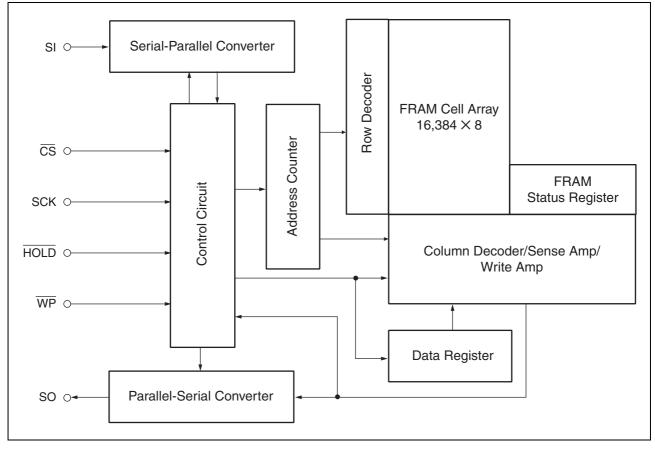


# ■ PIN FUNCTIONAL DESCRIPTIONS

Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chips select. When $\overline{CS}$ is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When $\overline{CS}$ is "L" level, device is in select (active) status. $\overline{CS}$ has to be "L" level before inputting op-code. The Chip Select pin is pulled up internally to the VDD pin.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■ WRITING PROTECT" for detail.
7	HOLD	Hold pin <u>This pin is used to interrupt serial input/output without making chips deselect. When</u> HOLD is "L" level, hold operation is activated, SO becomes High-Z, SCK and SI become do not care. While the hold operation, CS has to be retained "L" level.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin

# MB85RS128TY

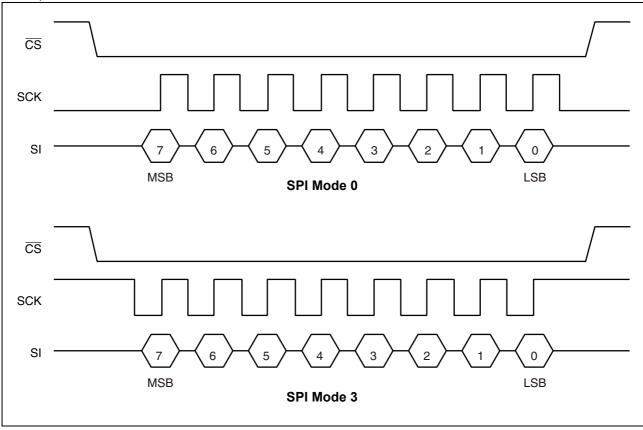
#### BLOCK DIAGRAM





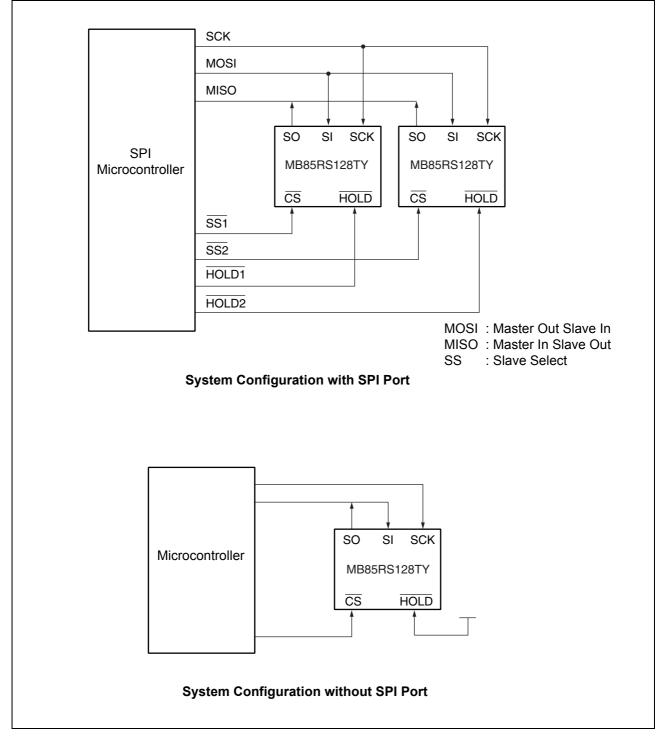
# SPI MODE

MB85RS128TY corresponds to the SPI mode 0 (CPOL = 0, CPHA = 0) , and SPI mode 3 (CPOL = 1, CPHA = 1) .



# ■ SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS128TY works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



# ■ STATUS REGISTER

Bit No.	Bit Name	Function
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.
6 to 4		Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.
1	WEL	Write Enable Latch         This indicates FRAM Array and status register are writable. The WREN         command is for setting, and the WRDI command is for resetting. With the         RDSR command, reading is possible but writing is not possible with the         WRSR command. WEL is reset after the following operations.         After power ON.         After WRDI command recognition.         The following rising edges do not reset WEL.         The rising edge of CS after WRSR command recognition.         The rising edge of CS after WRITE command recognition.
0	0	This is a bit fixed to "0".

# ■ OP-CODE

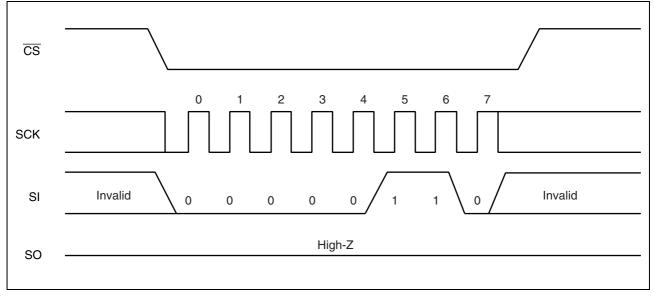
MB85RS128TY accepts 8 kinds of command specified in op-code. Op-code is a code composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If CS is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110 <sub>в</sub>
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011 <sub>в</sub>
WRITE	Write Memory Code	0000 0010 <sub>в</sub>
RDID	Read Device ID	1001 1111 <sub>в</sub>
SLEEP	Sleep Mode	1011 1001 <sub>B</sub>

# COMMAND

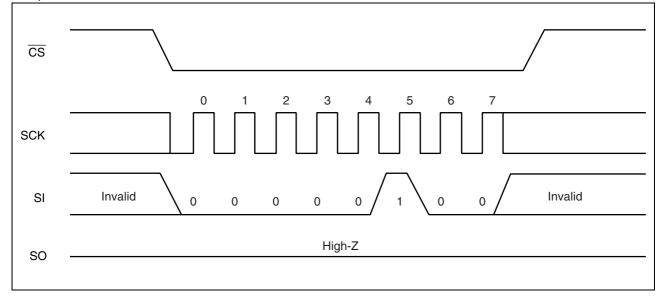
#### • WREN

The WREN command sets WEL (Write Enable Latch) bit to 1. WEL has to be set with the WREN command before writing operation (WRSR command and WRITE command). WREN command is applicable to "Up to 33 MHz operation".



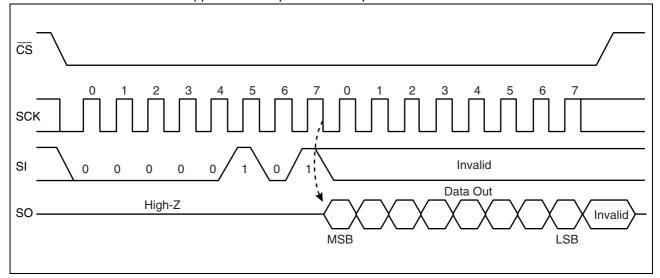
#### • WRDI

The WRDI command resets WEL (Write Enable Latch) bit to 0. Writing operation (WRSR command and WRITE command) are not performed when WEL is reset. WRDI command is applicable to "Up to 33 MHz operation".



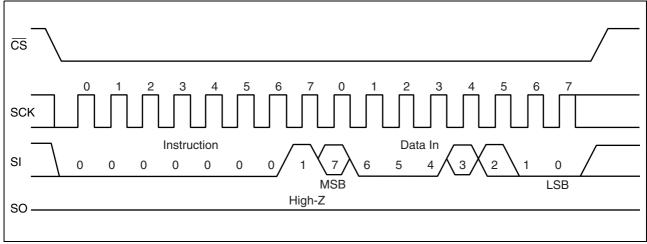
#### • RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of CS. RDSR command is applicable to "Up to 33 MHz operation".



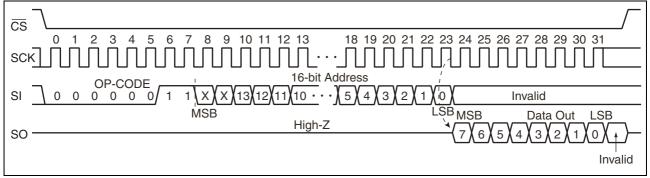
#### • WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0 of</u> the status register is fixed to "0" and cannot be written. The SI value corresponding to bit <u>0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the WP signal level until the end of command sequence. WRSR command is applicable to "Up to 33 MHz".



#### • READ

The READ command reads FRAM memory cell array data. Arbitrary 16 bits address and op-code of READ are input to SI. The upper two address bits are invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When CS is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before CS rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely. READ command is applicable to "Up to 33 MHz operation".



#### • WRITE

The WRITE command writes data to FRAM memory cell array. WRITE op-code, arbitrary 16 bits of address and 8 bits of writing data are input to SI. The upper two address bits are invalid. When 8 bits of writing data is input, data is written to FRAM memory cell array. Risen  $\overline{CS}$  will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before  $\overline{CS}$  rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely. WRITE command is applicable to "Up to 33 MHz operation".

0 1 2 3 4 5 6 SCK 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	7 8 9 10 11 12 13 18 19 20 П П П П П П П П П П П	) 21 22 23 24 25 26 27 28 29 30 31   □ □ □ □ □ □ □ □ □ □ □ □	
SI 0 0 0 0 0 0 1	<u>0                                    </u>	<u>2   1   0   7   6   5   4   3   2   1   0  </u> LSB'MSB LSI	
so	High-Z		

#### • RDID

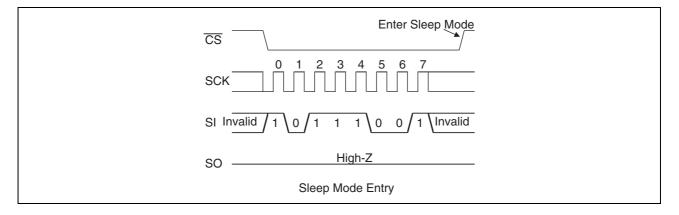
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, 32-bit Device ID is output by continuously sending SCK clock, and SO holds the output state of the last bit until CS is risen. RDID command is applicable to "Up to 33 MHz operation".

cs						• ·	••			
scк, 0 1 2 3 4 5 6 7 8 9 10 11 31 32 33 34 35 36 37 38 39										
SI1 0 0	SI 1 0 0 1 1 1 1 1 Invalid									
SO High-Z			́З <sup>.</sup> М		a Out 29)(28)		χε	3 (7)	Dat	a Out $\sqrt{4}\sqrt{3}\sqrt{2}\sqrt{1}\sqrt{0}$ LSB
				b	it				1	
	7	6	5	4	3	2	1	0	Hex	
Manufacturer ID	0	0	0	0	0	1	0	0	<b>04</b> н	Fujitsu
Continuation code	0	1	1	1	1	1	1	1	<b>7</b> Fн	
										·
	Prop	rietary	y use		0	Densit	у		Hex	
Product ID (1st Byte)	0	0	1	0	0	1	0	0	24н	Density: 00100 <sub>B</sub> = 128Kbit
		•			•		•			
		Proprietary use Hex								
Product ID (2nd Byte)	0	0	0	0	0	0	1	1	03н	

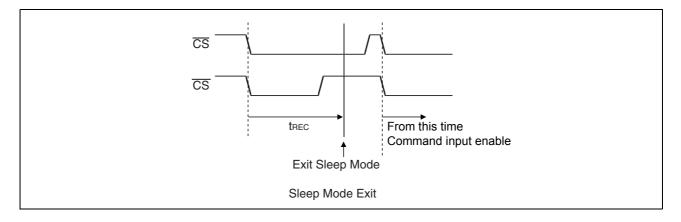
#### • SLEEP

The SLEEP command shifts the LSI to a low power mode called "SLEEP mode". The transition to the SLEEP mode is carried out at the rising edge of CS after operation code in the SLEEP command. However, when at least one SCK clock is inputted before the rising edge of CS after operation code in the SLEEP command, this SLEEP command is canceled.

After the SLEEP mode transition, SCK and SI inputs are ignored and SO changes to a High-Z state.



Returning to an normal operation from the SLEEP mode is carried out after  $t_{REC}$  (Max 400  $\mu$ s) time from the falling edge of  $\overline{CS}$  (see the figure below). It is possible to return  $\overline{CS}$  to H level before  $t_{REC}$  time. However, it is prohibited to bring down  $\overline{CS}$  to L level again during  $t_{REC}$  period.



# BLOCK PROTECT

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block
0	0	None
0	1	3000н to 3FFFн (upper 1/4)
1	0	2000н to 3FFFн (upper 1/2)
1	1	0000н to 3FFFн (all)

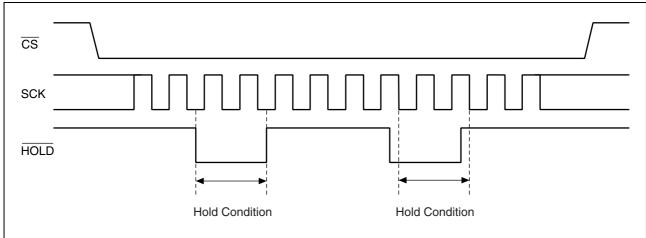
# WRITING PROTECT

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

# HOLD OPERATION

Hold status is retained without aborting a command if HOLD is "L" level while CS is "L" level. The timing for starting and ending hold status depends on the SCK to be "H" level or "L" level when a HOLD pin input is transited to the hold condition as shown in the diagram below. In case the HOLD pin transited to "L" level when SCK is "L" level, return the HOLD pin to "H" level at SCK being "L" level. In the same manner, in case the HOLD pin transited to "L" level when SCK is "H" level when SCK is "H" level when SCK is "H" level when SCK being "L" level. In the same manner, in case the HOLD pin transited to "L" level when SCK is "H" level, return the HOLD pin to "H" level at SCK being "L" level at SCK being "H" level. Arbitrary command operation is interrupted in hold status, SCK and SI inputs become do not care. And, SO becomes High-Z while reading command (RDSR, READ). If CS is rising during hold status, a command is aborted. In case the command is aborted before its recognition, WEL holds the value before transition to hold status.



# ■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rat	Unit		
	Symbol	Min	Мах	Unit	
Power supply voltage*	Vdd	- 0.5	+ 4.0	V	
Input voltage*	VIN	- 0.5	V <sub>DD</sub> + 0.5	V	
Output voltage*	Vout	- 0.5	V <sub>DD</sub> + 0.5	V	
Operation ambient temperature	TA	- 40	+ 125	°C	
Storage temperature	Tstg	- 55	+ 150	°C	

\*: These parameters are based on the condition that  $V_{SS}$  is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings. Do not exceed any of these ratings.

#### RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit			
Falameter	Symbol	Min	Тур	Мах	Onit	
Power supply voltage*1	Vdd	1.8	3.3	3.6	V	
Operation ambient temperature*2	TA	- 40		+ 125	°C	

\*1: These parameters are based on the condition that Vss is 0 V.

- \*2: Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.
- WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

# ELECTRICAL CHARACTERISTICS

# 1. DC Characteristics

#### (within recommended operating conditions)

Parameter	Symbol	ymbol Condition		Value			Unit
Farameter	Symbol	Condition	Min	Тур	Max	Unit	
		$0 \le \overline{CS} < V_{DD}$				200	
		$\overline{CS} = V_{DD}$	25 °C			1	
Input leakage current*1	lu		125 °C			2	μA
		WP, HOLD, SCK	25 °C			1	
		$SI = 0 V to V_{DD}$	125 °C			2	
Output leakage current*2	Ilo	SO = 0 V to V <sub>DD</sub>	25 °C			1	Δ
Output leakage current	μισι		125 °C			2	μA
Operating power supply current <sup>*3</sup>	ldd	SCK = 33 MHz	SCK = 33 MHz		_	2.3	mA
Standby current	lsв	$\frac{SCK}{WP} = \frac{SI}{HOLD} = V_{1}$				45	μA
Sleep current	lzz	CS = V <sub>DD</sub> All inputs Vss or V	/ <sub>DD</sub>			12	μA
Input high voltage	Vін	V <sub>DD</sub> = 1.8 V to 3.6	V <sub>DD</sub> = 1.8 V to 3.6 V			$V_{\text{DD}} + 0.5$	V
Input low voltage	VIL	V <sub>DD</sub> = 1.8 V to 3.6 V		- 0.5		$V_{\text{DD}} \times 0.2$	V
Output high voltage	Vон	Iон = - 2 mA		$V_{\text{DD}}-0.5$			V
Output low voltage	Vol	$I_{OL} = 2 \text{ mA}$				0.4	V
Pull up resistance for $\overline{CS}$	R₽	—		18	33	80	kΩ

\*1 : Applicable pin :  $\overline{CS}$ ,  $\overline{WP}$ ,  $\overline{HOLD}$ , SCK, SI

\*2 : Applicable pin : SO

\*3 : Input voltage magnitude : VDD – 0.2 V or VSS

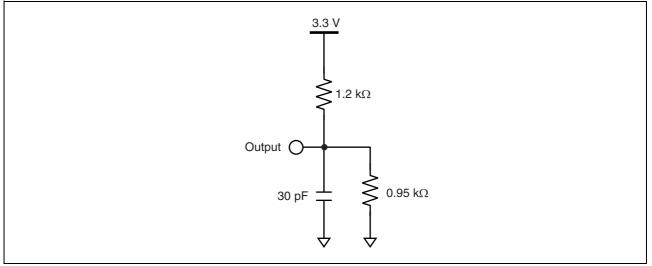
# 2. AC Characteristics

Parameter	Symbol	v	Unit	
Faidilielei	Symbol	Min	Мах	
SCK clock frequency	fск	0	33	MHz
Clock high time	tсн	13	—	ns
Clock low time	tc∟	13	—	ns
Chip select set up time	<b>t</b> csu	10	—	ns
Chip select hold time	tсsн	10	—	ns
Output disable time	top		16	ns
Output data valid time	todv		13	ns
Output hold time	tон	0	—	ns
Deselect time	t⊳	40	—	ns
Data in rising time	tR	_	50	ns
Data falling time	t⊧	_	50	ns
Data set up time	<b>t</b> su	5	—	ns
Data hold time	tн	5	—	ns
HOLD set uptime	<b>t</b> Hs	10	—	ns
HOLD hold time	tнн	10	—	ns
HOLD output floating time	tнz		20	ns
HOLD output active time	t∟z		20	ns
SLEEP recovery time	trec	_	400	μS

# **AC Test Condition**

Power supply voltage	: 1.8 V to 3.6 V Operation
Operation ambient temperature	: - 40 °C to + 125 °C
Input voltage magnitude	: $V_{\text{DD}}  imes 0.8 \le V_{\text{IH}} \le V_{\text{DD}}$
	$0 \leq V_{\text{IL}} \leq V_{\text{DD}} \times 0.2$
Input rising time	: 5 ns
Input falling time	: 5 ns
Input judge level	: Vdd/2
Output judge level	: Vdd/2

## AC Load Equivalent Circuit

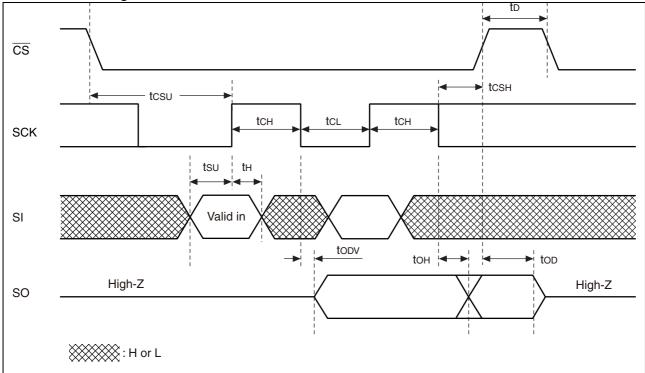


# 3. Pin Capacitance

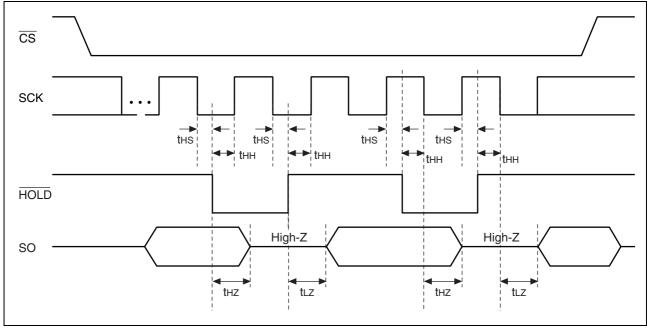
Parameter	Symbol	Condition	Va	lue	Unit
Farameter	Symbol	Condition	Min	Max	Onit
Output capacitance	Co	$V_{DD} = 3.3 \text{ V},$ $V_{IN} = V_{OUT} = 0 \text{ V to } V_{DD},$	_	8	pF
Input capacitance	Cı	$f = 1 \text{ MHz}, T_A = +25 \text{ °C}$		6	pF

### TIMING DIAGRAM

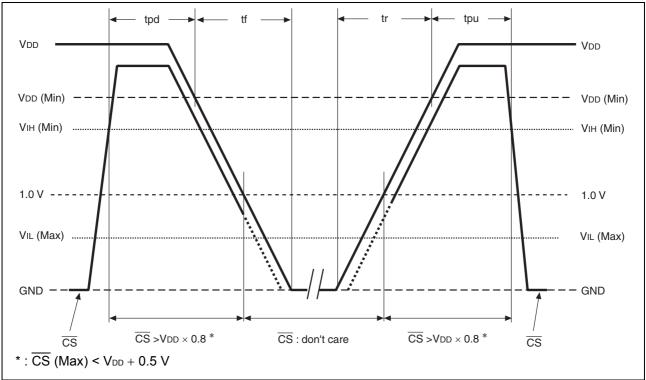




#### • Hold Timing



# POWER ON/OFF SEQUENCE



Parameter	Symbol	Va	Unit		
Falanetei	Symbol	Min	Max	onit	
CS level hold time at power OFF	tpd	400		ns	
CS level hold time at power ON	tpu	250		μS	
Power supply rising time	tr	0.05		ms/V	
Power supply falling time	tf	0.1		ms/V	

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

# ■ FRAM CHARACTERISTICS

Parameter	Value		Unit	Remarks
Falameter	Min	Мах	Unit	Remarks
Read/Write Endurance <sup>*1</sup>	10 <sup>13</sup>		Times/byte	Operation Ambient Temperature $T_A = +85 \ ^{\circ}C$
	2.5 or more*3			Operation Ambient Temperature $T_A = +125 \ ^{\circ}C$
Data Retention <sup>*2</sup>	8.2		Years	Operation Ambient Temperature $T_A = +105 \ ^{\circ}C$
	10 —			Operation Ambient Temperature $T_A = +85 \ ^{\circ}C$

\*1 : Total number of reading and writing defines the minimum value of endurance, as an FRAM memory operates with destructive readout mechanism.

\*2: Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

\*3: Under evaluation for more than 2.5 years (+125  $^\circ\text{C}).$ 

# NOTE ON USE

We recommend programming of the device after reflow. Data written before reflow cannot be guaranteed.



#### ■ ESD AND LATCH-UP

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥  2000 V
ESD MM (Machine Model) JESD22-A115 compliant		≥  200 V
ESD CDM (Charged Device Model) JESD22-C101 compliant	MB85RS128TYPNF-G-BCE1	≥  1000 V
Latch-Up (I-test) JESD78 compliant	-	≥  125 mA
Latch-Up (V <sub>supply</sub> overvoltage test) JESD78 compliant		≥ 5.4V

# REFLOW CONDITIONS AND FLOOR LIFE

[ JEDEC MSL ] : Moisture Sensitivity Level 3 (ISP/JEDEC J-STD-020D)

#### Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.



# ORDERING INFORMATION

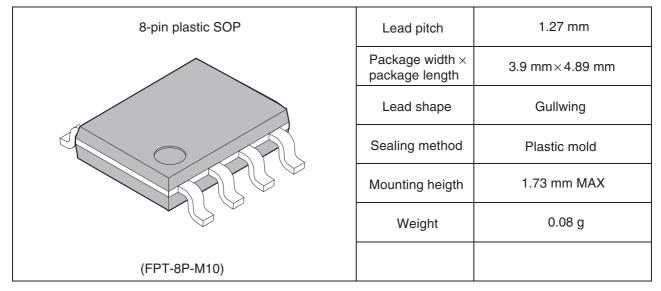
Part number	Package	Shipping form	Minimum shipping quantity
MB85RS128TYPNF-G-BCE1	8-pin plastic SOP (FPT-8P-M10)	Tube	*
MB85RS128TYPNF-G-BCERE1	8-pin plastic SOP (FPT-8P-M10)	Embossed Carrier tape	1500

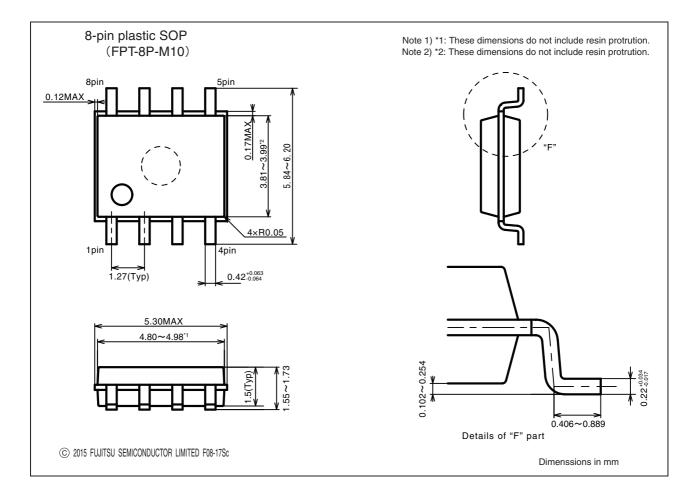
\* : Please contact our sales office about minimum shipping quantity.



# MB85RS128TY

#### ■ PACKAGE DIMENSION





# ■ MARKING (Example)

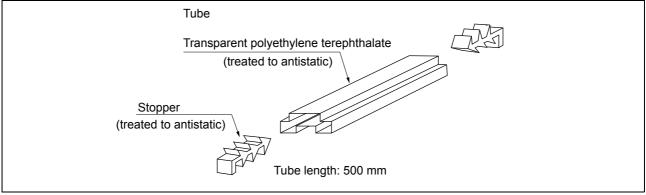
<text>

### ■ PACKING INFORMATION

#### 1. Tube

#### 1.1 Tube Dimensions

Tube/stopper shape

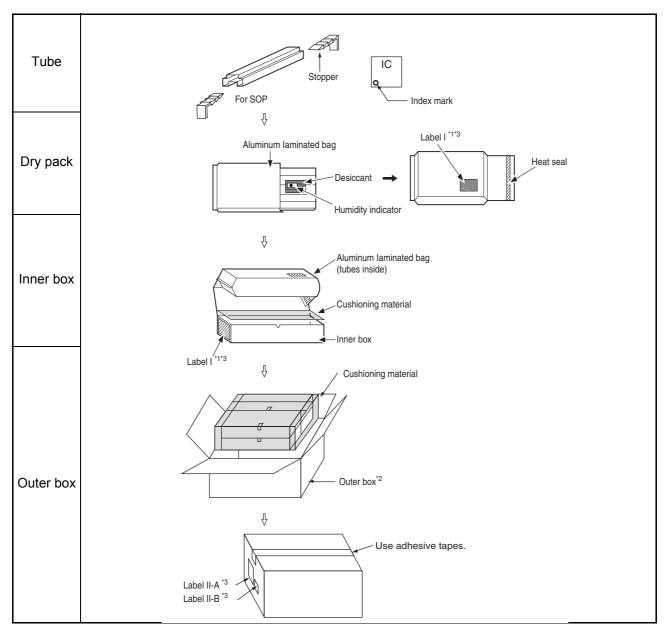


#### Tube cross-sections and Maximum quantity

		Ν	laximum qua	antity
Package form	Package code	pcs/ tube	pcs/inner box	pcs/outer box
SOP, 8, plastic (2)	FPT-8P-M10	85	4250	17000
t = 0.6 Transparent polyethylene terephthalate				

(Dimensions in mm)

#### 1.2 Tube Dry pack packing specifications



\*1: For a product of witch part number is suffixed with "E1", a " G (\*)" marks is display to the moisture barrier bag and the inner boxes.

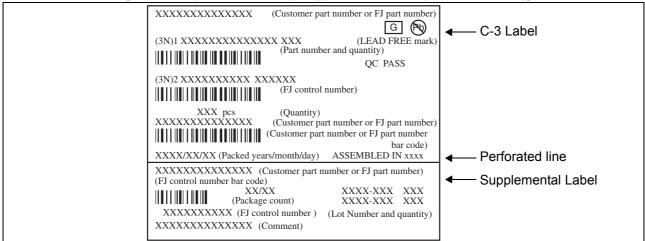
\*2: The space in the outer box will be filled with empty inner boxes, or cushions, etc.

\*3: Please refer to an attached sheet about the indication label.

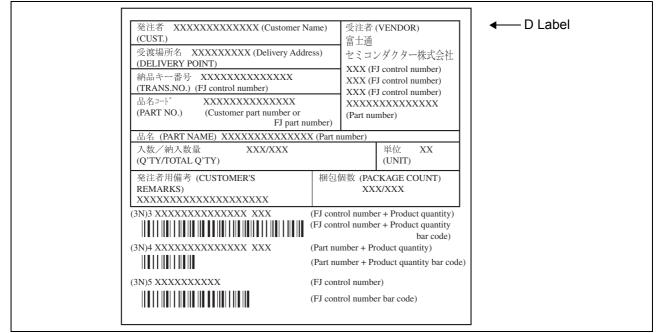
Note: The packing specifications may not be applied when the product is delivered via a distributor.

#### 1.3 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



Label II-A: Label on Outer box [D Label] (100mm × 100mm)



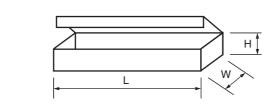
#### Label II-B: Outer boxes product indicate

XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX	art number)		
(Lot Number) XXXX-XXX XXXX-XXX	(Count) X箱 X箱	(Quantity) XXX 個 XXX 個 XXX 個	

Note: Depending on shipment state, "Label II-A" and "Label II-B" on the external boxes might not be printed.

# 1.4 Dimensions for Containers

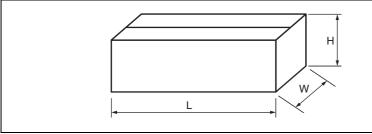
### (1) Dimensions for inner box



L	W	Н
533	124	73

(Dimensions in mm)

#### (2) Dimensions for outer box

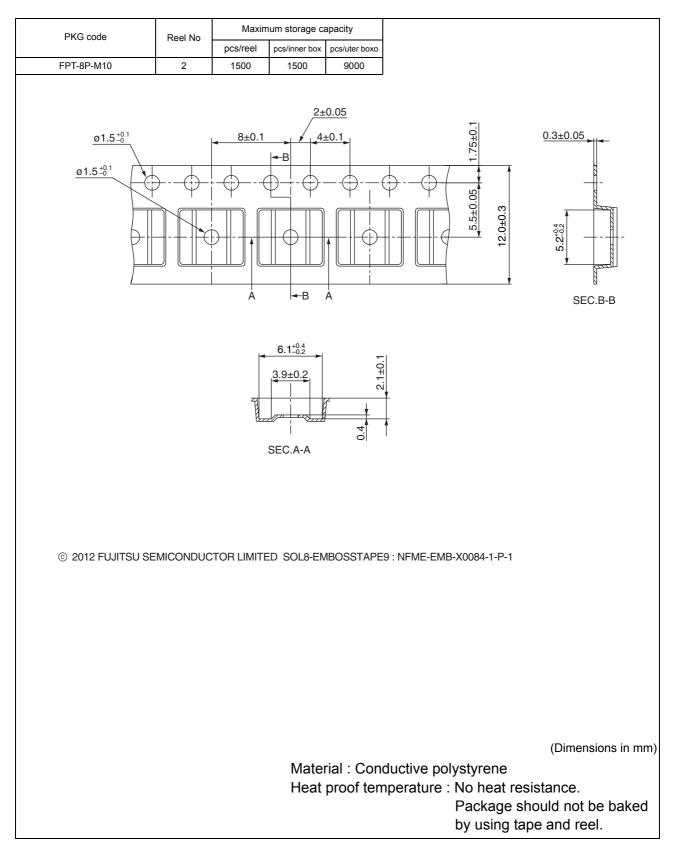


L	W	Н
549	277	180

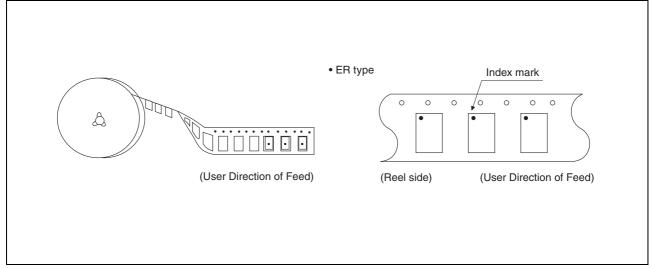
(Dimensions in mm)

### 2. Emboss Tape (FPT-8P-M10)

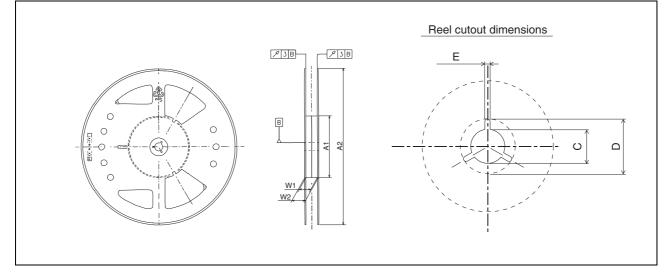
#### 2.1 Tape Dimensions



#### 2.2 IC orientation



#### 2.3 Reel dimensions



					Dimensio	ns in mm
A1	A2	С	D	E	W1	W2
100±1	254±2	13±0.2	21±0.8	2±0.5	13.5±1.0	17.5±1.0

# MB85RS128TY

2.4Taping	(¢254mm	Reel) D	ry Pack	Packing	Specifications
-----------	---------	---------	---------	---------	----------------

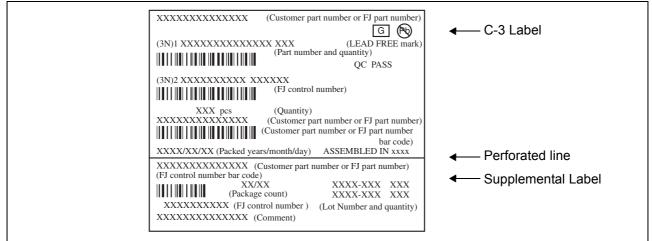
1	Storage ICs in Embossed tape with designated numbers and direction, and wind it to the reel. Storage capacity: 1500pcs/tape	Reel(\$\phi 254) Embossed tape C-3 Label + Supplemental Label 1,*4 Embossed tape
		lead direction
2	Put an C-3 Label and Supplemental Label including part number, lot number and capacity on the specified reel area.	C-3 Label + Supplemental Label *1,*4
3	Put Humidity Indicator and two Desiccants on the reel, and put into an Aluminum laminated bag.	Aluminum laminated bag Humidity Indicator Desiccant (40g) C-3 Label + Supplemental Label *1,*4
4	Seal Aluminum laminated bag with simple vacuum packing.	Heat seal
5	Put C-3 Label ,Supplemental Label and MSL label not to cover the indication of Aluminum laminated bag.	MSL label + Supplemental Label *1,*4
6	Put the Aluminum laminated bag including reel into Inner box, and tape the Inner box.	Inner box
7	Put C-3 Label and Supplemental Label on the specified area of Inner box.	Adhesive tape C-3 Label + Supplemental Label *1,*4
8	Put Inner boxes (max 6 boxes with 3-stage and 2 columns) into an Outer box. * Outer box storage capacity: 6 Inner boxes (max) 9000pcs (max) = 1500 pcs / Inner box x 6 Inner boxes	Inner box (max 6) Outer box *2,*3 (corrugated cardboard)
9	Close the cover of Outer box and fasten with adhesive tape.	D Label *4 Outer box product indication *4

- \*1: For a product of witch part number is suffixed with "E1", a " G () "marks is display to the moisture barrier bag and the inner boxes.
- \*2: The size of the outer box may be changed depending on the quantity of inner boxes.
- \*3: The space in the outer box will be filled with empty inner boxes, or cushions, etc.
- \*4: Please refer to an attached sheet about the indication label.
- : The packing specifications may not be applied when the product is delivered via a distributor.

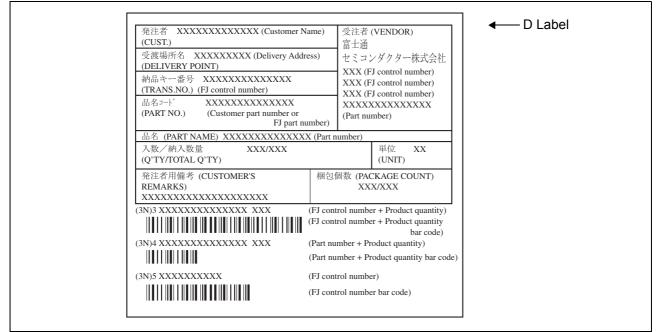


#### 2.5 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



Label II-A: Label on Outer box [D Label] (100mm × 100mm)



#### Label II-B: Outer boxes product indicate

XXXXXXXXXXXXXXXX	(Part number)		
(Lot Number) XXXX-XXX XXXX-XXX	(Count) X箱 X箱 計	(Quantity) XXX 個 XXX 個 XXX 個	

Note: Depending on shipment state, "Label II-A" and "Label II-B" on the external boxes might not be printed.

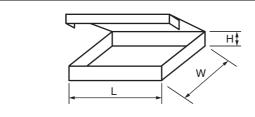
# MB85RS128TY

Label III:Moisture Barrier Bag (It sticks it on the Aluminum laminated bag) [MSL Label (100mm × 70mm)]

Caution LEVEL This bag contains MOISTURE-SENSITIVE DEVICES	< MSL label
1. Calculated shelf life in sealed bag: 12 months at ${<}40^{\circ}\text{C}$ and ${<}90\%$ relative humidity (RH)	
2. Peak package body temperature: 260°C	
<ul> <li>3. After bag is opened, devices that will be subjected to reflow solder or other high temperature process must be</li> <li>a) Mounted within: 168 hours of factory conditions &lt;30°C/60% RH, or</li> <li>b) Stored per J-STD-033</li> </ul>	
<ul> <li>4. Devices require bake, before mounting, if:</li> <li>a) Humidity Indicator Card reads &gt;10% for level 2a - 5a devices or &gt;60% for level 2 devices when read at 23 ± 5°C</li> <li>b) 3a or 3b are not met</li> </ul>	
5. If baking is required, refer to IPC/JEDEC J-STD-033 for bake procedure	
Bag Seal Date: see adjacent bar code label.	
Note: Level and body temperature defined by IPC/JEDEC J-STD-020 <b>Fujitsu Semiconductor Limited</b>	

# 2.6 Dimensions for Containers

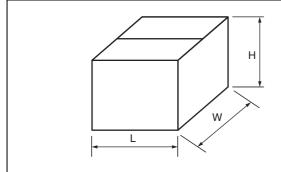
#### (1) Dimensions for inner box



Tape width	L	W	н
12	265	262	51

(Dimensions in mm)

#### (2) Dimensions for outer box



L	W	Н
549	277	180

(Dimensions in mm)

# ■ MAJOR CHANGES IN THIS EDITION

A change on a page is indicated by a vertical line drawn left side of that page.

Page	Section	Change Results
		Data retention is prolonged.
1	■FEATURES	1year(125 °C), 10years(85 °C)
		> 2.5years(125 °C), 8.2years(105 °C), 30years(85 °C)
		Data retention is prolonged.
18	■FRAM CHARACTERISTICS	1year(125 °C), 10years(85 °C)
		> 2.5years(125 °C), 8.2years(105 °C), 30years(85 °C)
23-32	■PACKING INFORMATION	Packing information for both tube and emboss tape are added.



# **FUJITSU SEMICONDUCTOR LIMITED**

Shin-Yokohama Chuo Building, 2-100-45 Shin-Yokohama, Kohoku-ku, Yokohama, Kanagawa 222-0033, Japan *http://jp.fujitsu.com/fsl/en/* 

#### All Rights Reserved.

FUJITSU SEMICONDUCTOR LIMITED, its subsidiaries and affiliates (collectively, "FUJITSU SEMICONDUCTOR") reserves the right to make changes to the information contained in this document without notice. Please contact your FUJITSU SEMICONDUCTOR sales representatives before order of FUJITSU SEMICONDUCTOR device. Information contained in this document, such as descriptions of function and application circuit examples is presented solely for reference to examples of operations and uses of FUJITSU SEMICONDUCTOR device. FUJITSU SEMICONDUCTOR disclaims

any and all warranties of any kind, whether express or implied, related to such information, including, without limitation, quality, accuracy, performance, proper operation of the device or non-infringement. If you develop equipment or product incorporating the FUJITSU SEMICONDUCTOR device based on such information, you must assume any responsibility or liability arising out of or in connection with such information or any use thereof. FUJITSU SEMICONDUCTOR assumes no responsibility or liability for any damages whatsoever arising out of or in connection with such information or any use thereof.

Nothing contained in this document shall be construed as granting or conferring any right under any patents, copyrights, or any other intellectual property rights of FUJITSU SEMICONDUCTOR or any third party by license or otherwise, express or implied. FUJITSU SEMICONDUCTOR assumes no responsibility or liability for any infringement of any intellectual property rights or other rights or other rights of third parties resulting from or in connection with the information contained herein or use thereof.

The products described in this document are designed, developed and manufactured as contemplated for general use including without limitation, ordinary industrial use, general office use, personal use, and household use, but are not designed, developed and manufactured as contemplated (1) for use accompanying fatal risks or dangers that, unless extremely high levels of safety is secured, could lead directly to death, personal injury, severe physical damage or other loss (including, without limitation, use in nuclear facility, aircraft flight control system, air traffic control system, mass transport control system, medical life support system and military application), or (2) for use requiring extremely high level of reliability (including, without limitation, submersible repeater and artificial satellite). FUJITSU SEMICONDUCTOR shall not be liable for you and/or any third party for any claims or damages arising out of or in connection with above-mentioned uses of the products.

Any semiconductor devices fail or malfunction with some probability. You are responsible for providing adequate designs and safeguards against injury, damage or loss from such failures or malfunctions, by incorporating safety design measures into your facility, equipments and products such as redundancy, fire protection, and prevention of overcurrent levels and other abnormal operating conditions.

The products and technical information described in this document are subject to the Foreign Exchange and Foreign Trade Control Law of Japan, and may be subject to export or import laws or regulations in U.S. or other countries. You are responsible for ensuring compliance with such laws and regulations relating to export or re-export of the products and technical information described herein. All company names, brand names and trademarks herein are property of their respective owners.